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ACFL-6211T, ACFL-6212T

Automotive High-Speed, Low-Power Digital Optocoupler with R²Coupler® Isolation in a Stretched 12-Pin Surface Mount Plastic Package



Data Sheet

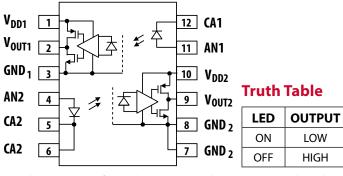
Description

The ACFL-6211T and ACFL-6212T are automotive grade dual channel, bi-directional, high speed digital CMOS optocouplers. The stretched SO-12 stretched package outline is designed to be compatible with standard surface mount processes and occupies the same land area as their single channel equivalent, ACPL-K71T and ACPL-K72T, in stretched SO8 package.

This digital optocoupler uses an insulating layer between the light emitting diode and an integrated photo detector to provide electrical insulation between input and output. Each channel of the digital optocoupler has a CMOS detector IC with an integrated photodiode, a high speed trans-impedance amplifier, and a voltage comparator with an output driver. Each channel is also isolated from the other.

Broadcom R²Coupler technology provides reinforced insulation and reliability that delivers safe signal isolation critical in automotive and high temperature industrial applications.

Functional Diagram



Note: The connection of a 1 μF bypass capacitor between pins 1 and 3 and pins 8 and 10 is recommended.

Features

- Qualified to AEC Q100 Grade 1 Test Guidelines
- Automotive Wide Temperature Range: –40°C to +125°C
- 5V CMOS compatibility
- 40 kV/µs Common-Mode Rejection at VCM=1000V (typ)
- Low Propagation Delay:
- ACFL-6211T: 25 ns at I_F = 10 mA (typ)
- ACFL-6212T: 60 ns at I_F = 4 mA (typ)
- Compact, Auto-Insertable Stretched SO12 Packages
- Worldwide Safety Approval:
 - UL 1577 recognized, 5 kV_{RMS}/1 min.
 - CSA Approved
 - IEC/EN/DIN EN 60747-5-5

Features

- Automotive IPM Driver for DC-DC converters and motor inverters
- CANBus and SPI Communications Interface
- High Temperature Digital/Analog Signal Isolation
- Power Transistor Isolation

CAUTION: It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation which may be induced by ESD. The components featured in this datasheet are not to be used in military or aerospace applications or environments.

Pin Description

Pin No.	Pin Name	Description
1	V_{DD1}	Primary Side Power Supply
2	V _{OUT1}	Output 1
3	GND1	Primary Side Ground
4	AN2	Anode 2
5	CA2	Cathode 2
6	CA2	Cathode 2

Pin No.	Pin Name	Description				
7	GND2	Secondary Side Ground				
8	GND2	Secondary Side Ground				
9	V _{OUT2}	Output 2				
10	V _{DD2}	Secondary Side Power Supply				
11 AN1		Anode 1				
12	CA1	Cathode 1				

Ordering Information

Part Number	Option (RoHS Compliant)	Package	Surface Mount	Tape and Reel	UL 5000 Vrms/ 1 Minute rating	IEC/EN/DIN EN 60747-5-5	Quantity
ACFL-6211T	-000E	Stretched	X		X		80 per tube
	-060E	SO-12	Х		X	X	80 per tube
	-500E		Х	Х	X		1000 per reel
	-560E		X	X	X	X	1000 per reel
ACFL-6212T	-000E	Stretched	Х		X		80 per tube
	-060E	SO-12	Х		X	X	80 per tube
	-500E		X	X	X		1000 per reel
	-560E		Х	Х	X	X	1000 per reel

To order, choose a part number from the part number column and combine with the desired option from the option column to form an order entry.

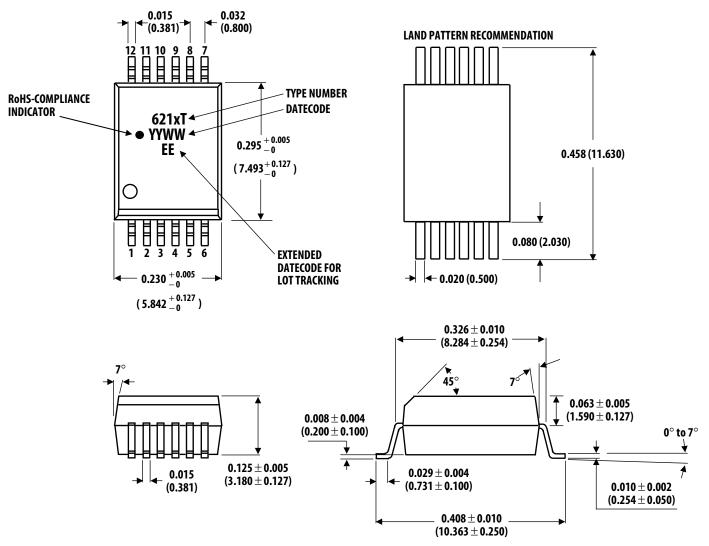
Example 1:

ACFL-6212T-560E to order product of SSO-12 Surface Mount package in Tape and Reel packaging with IEC/EN/DIN EN 60747-5-5 Safety Approval in RoHS compliant.

Option datasheets are available. Contact your Broadcom sales representative or authorized distributor for information.

Package Outline Drawing

12-Lead Surface Mount



Dimensions in inches (millimeters)

Lead coplanarity = 0.004 inches (0.1 mm)

Recommended Pb-Free IR Profile

Recommended reflow condition as per JEDEC Standard, J-STD-020 (latest revision).

Note: Non-halide flux should be used

Regulatory Information

The ACFL-6211T and ACFL-6212T are approved by the following organizations:

UL 1577, component recognition program up to $V_{ISO} = 5 \text{ kV}_{RMS}$				
CSA Approved under CSA Component Acceptance Notice #5				
IEC/EN/DIN EN 60747-5-5	Approved under IEC/EN/DIN EN 60747-5-5			

Insulation and Safety Related Specifications

Parameter	Symbol	ACFL-6211T/ ACFL-6212T	Unit	Conditions
Minimum External Air Gap (Clearance)	L(101)	8.3	mm	Measured from input terminals to output terminals, shortest distance through air.
Minimum External Tracking (Creepage)	L(102)	8.5	mm	Measured from input terminals to output terminals, shortest distance path along body.
Minimum Internal Plastic Gap (Internal Clearance)		0.08	mm	Through insulation distance conductor to conductor, usually the straight line distance thickness between the emitter and detector.
Tracking Resistance (Comparative Tracking Index)	СТІ	175	V	DIN IEC 112/VDE 0303 Part 1
Isolation Group (DIN VDE0109)		IIIa		Material Group (DIN VDE 0109)

IEC/EN/DIN EN 60747-5-5 Insulation Related Characteristic (Option 060E and 560E)

Description	Symbol	Characteristic	Unit
Installation classification per DIN VDE 0110/1.89, Table 1 for rated mains voltage ≤ 600V _{RMS} for rated mains voltage < 1000V _{RMS}		I-III I-III	
Climatic Classification		40/125/21	
Pollution Degree (DIN VDE 0110/1.89)		2	
Maximum Working Insulation Voltage	V _{IORM}	1140	V _{PEAK}
Input to Output Test Voltage, Method b $V_{IORM} \times 1.875 = V_{PR}$, 100% Production Test with $t_m = 1$ sec, Partial Discharge < 5 pC	V _{PR}	2137	V _{PEAK}
Input to Output Test Voltage, Method a V _{IORM} x 1.6 = V _{PR} , Type and sample test, t _m = 10 sec, Partial Discharge < 5 pC	V _{PR}	1824	V _{PEAK}
Highest Allowable Overvoltage (Transient Overvoltage, t _{ini} = 60 sec)	V _{IOTM}	6000	V _{PEAK}
Safety Limiting Values (Maximum values allowed in the event of a failure) Case Temperature Input Current Output Power	T _S Is,input Ps,output	175 230 600	°C mA mW
Insulation Resistance at T _S , V _{IO} = 500V	R _S	10 ⁹	Ω

Absolute Maximum Ratings

Parameter	Symbol	Min.	Max.	Unit	Condition			
Storage Temperature	T _S	-55	+150	°C				
Ambient Operating Temperature [1]	T _A	-40	+125	°C				
Junction Temperature	Tj		+150	°C				
Supply Voltages	V _{DD}	0	6.5	V				
Output Voltage	Vo	-0.5	V _{DD} + 0.5	V				
Average Forward Input Current	IF		20.0	mA				
Peak Transient Input Current (I _F at 1 μs pulse width, <10% duty cycle)	I _{F(TRAN)}		1 80	A mA	≤1 µs Pulse Width, 300 pps ≤1 µs Pulse Width, <10% Duty Cycle			
Reverse Input Voltage	V _r		5	V				
Input Power Dissipation	P _I		40	mW				
Average Output Current	lo		10	mA				
Output Power Dissipation	Ро		30	mW				
Lead Solder Temperature	260°C for 10 sec., 1.6 mm below seating plane							
Solder Reflow Temperature Profile	See Solder Re	flow Tempera	ature Profile S	Section				

Recommended Operating Conditions

Parameter	Symbol	Min.	Max.	Unit	Note
Supply Voltage	V_{DD}	3.0	5.5	V	
Operating Temperature	T _A	-40	+125	°C	
Forward Input Current	I _{F(ON)}	4.0	15	mA	
Forward Off State Voltage	V _{F(OFF)}		0.8	V	
Input Threshold Current	I _{TH}		3.5	mA	

Electrical Specifications

Over recommended operating conditions. All typical specifications are at $T_A = 25$ °C, $V_{DD} = 5$ V.

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Conditions	Fig.
LED Forward Voltage	V _F	1.45	1.5	1.75	V	I _F = 10 mA, T _A = 25°C	
		1.25	1.5	1.85	V	I _F = 10 mA	
VF Temperature Coefficient			-1.5		mV/°C		
Input Threshold Current	I _{TH}		1.3	3.5	mA		2
Input Capacitance	C _{IN}		90		pF		
Input Reverse Breakdown Voltage	BV _R	5.0			V	Ι _R = 10 μΑ	
Logic High Output Voltage	V _{OH}	V _{DD} – 0.6			V	I _{OH} = −3.2 mA	4
Logic Low Output Voltage	V _{OL}			0.6	V	I _{OL} = 4 mA	3
Logic Low Output Supply Current (per channel)	I _{DDL}		0.9	1.5	mA		
Logic High Output Supply Current (per channel)	I _{DDH}		0.9	1.5	mA		

ACFL-6211T High Speed Mode Switching Specifications

Over recommended operating conditions: $T_A = -40^{\circ}\text{C}$ to $+125^{\circ}\text{C}$, $4.5\text{V} \le \text{V}_{DD} \le 5.5\text{V}$. All typical specifications are at $T_A = 25^{\circ}\text{C}$, $V_{DD} = 5\text{V}$.

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Conditions	Fig.	Note
Propagation Delay Time to Logic Low Output	t _{PHL}		25	35	ns	$V_{in} = 4.5V \text{ to } 5.5V,$ $R_{in} = 390\Omega \pm 5\%,$	5, 9, 11	1, 2, 3
Propagation Delay Time to Logic High Output	t _{PLH}		25	35	ns	$C_{in} = 100 \text{ pF}, C_L = 15 \text{ pF}$		
Pulse Width Distortion	PWD		0	12	ns	Output low threshold = 0.8V		
Propagation Delay Skew	t _{PSK}			15	ns	Output high threshold =		
Output Rise Time (10% to 90%)	t _R		10		ns	80% of Vdd		
Output Fall Time (90% to 10%)	t _F		10		ns			
Common Mode Transient Immunity at Logic High Output	CM _H	15	25		kV/μs	$V_{in} = 0V$, $R_{in} = 390\Omega \pm 5\%$, $C_{in} = 100$ pF, $V_{cm} = 1000V$, $T_A = 25^{\circ}C$		4
Common Mode Transient Immunity at Logic High Output	CM _L	15	25		kV/μs	$V_{in} = 4.5V \text{ to } 5.5V \text{ ,} \\ R_{in} = 390\Omega \pm 5\%, \\ C_{in} = 100 \text{ pF, } V_{cm} = 1000V, \\ T_{A} = 25^{\circ}\text{C}$		5

ACFL-6212T Low Power Mode Switching Specifications

Over recommended operating conditions: $T_A = -40^{\circ}\text{C}$ to $+125^{\circ}\text{C}$, $3.0\text{V} \le \text{V}_{DD} \le 5.5\text{V}$. All typical specifications at 25°C and $\text{V}_{DD} = 5\text{V}$.

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Conditions	Fig.	Note
Propagation Delay Time to Logic Low Output	t _{PHL}		60	100	ns	$I_F = 4 \text{ mA, C}_L = 15 \text{ pF}$	7, 12	1, 2, 3
Propagation Delay Time to Logic High Output	t _{PLH}		35	100	ns			
Pulse Width Distortion	PWD		25	50	ns			
Propagation Delay Skew	t _{PSK}			60	ns			
Output Rise Time (10% to 90%)	t _R		10		ns			
Output Fall Time (90% to 10%)	t _F		10		ns			
Common Mode Transient Immunity at Logic High Output	CM _H	25	40		kV/μs	Using Broadcom LED Driving Circuit, V_{IN} = 0V, R_1 = 330 Ω ±5%, R_2 = 330 Ω ±5%, V_{CM} = 1000V, T_A = 25°C		4
Common Mode Transient Immunity at Logic Low Output	CM _L	25	40		kV/μs	Using Broadcom LED Driving Circuit, $V_{IN}=4.5 \text{ to } 5.5\text{V},$ $R_1=330\Omega\pm5\%,$ $R_2=330\Omega\pm5\%,$ $V_{CM}=1000\text{V}, T_A=25^{\circ}\text{C}$		5

Package Characteristics

All Typical at $T_A = 25$ °C.

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Conditions	Notes
Input-Output Momentary Withstand Voltage	V _{ISO}	5000			V _{RMS}	RH \leq 50%, t = 1 min. T _A = 25°C	6, 7
Input-Output Resistance	R _{I-O}		10 ¹⁴		W	$V_{I-O} = 500V_{dc}$	6
Input-Output Capacitance	C _{I-O}		0.6		pF	f = 1 MHz, T _A = 25°C	6

Notes:

- 1. t_{PHL} propagation delay is measured from the 50% (V_{IN} or I_F) on the rising edge of the input pulse to the 0.8V of V_{DD} of the falling edge of the V_O signal. t_{PLH} propagation delay is measured from the 50% (V_{IN} or I_F) on the falling edge of the input pulse to the 80% level of the rising edge of the V_O signal.
- 2. PWD is defined as $|t_{PHL} t_{PLH}|$.
- 3. t_{PSK} is equal to the magnitude of the worst case difference in t_{PHL} and/or t_{PLH} that will be seen between units at any given temperature within the recommended operating conditions.
- 4.~~ CM_H is the maximum tolerable rate of rise of the common mode voltage to assure that the output will remain in a high logic state.
- 5. CM_L is the maximum tolerable rate of fall of the common mode voltage to assure that the output will remain in a low logic state.
- 6. Device considered a two terminal device: pins 1 to 6 shorted together, and pins 7 to 12 shorted together.
- 7. In accordance with UL 1577, each optocoupler is proof tested by applying an insulation test voltage $> 6000V_{RMS}$ for 1 second.

Typical Performance Plots

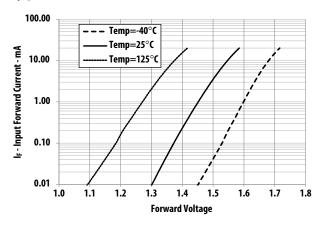


Figure 1: Typical Diode Input Forward Current Characteristic

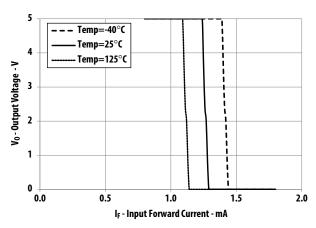


Figure 2: Typical Output Voltage vs. Input Forward Current

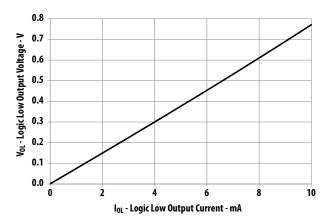


Figure 3: Typical Logic Low Output Voltage vs. Logic Low Output Current

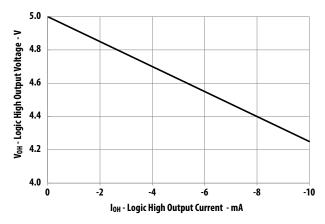


Figure 4: Typical Logic High Output Voltage vs. Logic High Output Current

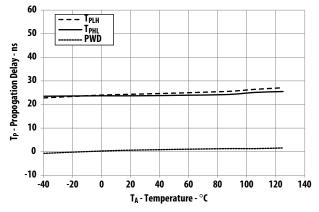


Figure 5: ACFL-6211T (High Speed) Typical Propagation Delay vs. Temperature, V_{IN} =4.5V, R_{IN} =390 Ω , C_{IN} =100 pF

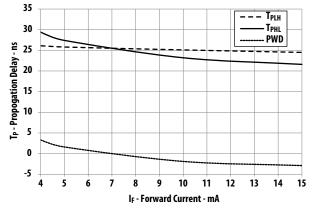


Figure 6: ACFL-6211T (High Speed) Typical Propagation Delay vs. Input Forward Current, V_{IN} =4.5V, R_{IN} =390 Ω , C_{IN} =100 pF, T_A =25°C

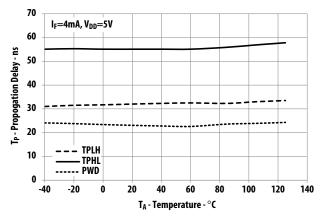


Figure 7. ACFL-6212T (5V) Typical Propagation Delay vs. Temperature

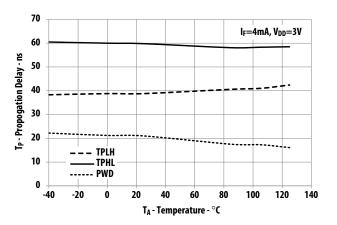


Figure 9. ACFL-6212T (3V) Typical Propagation Delay vs. Temperature

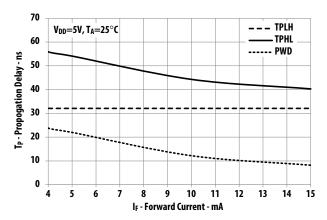


Figure 8. ACFL-6212T (5V) Typical Propagation Delay vs. Input Forward Current

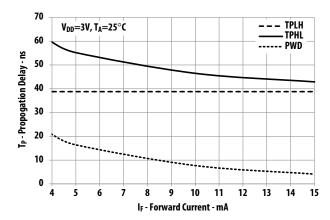


Figure 10. ACFL-6212T (3V) Typical Propagation Delay vs. Input Forward Current

Application Circuits

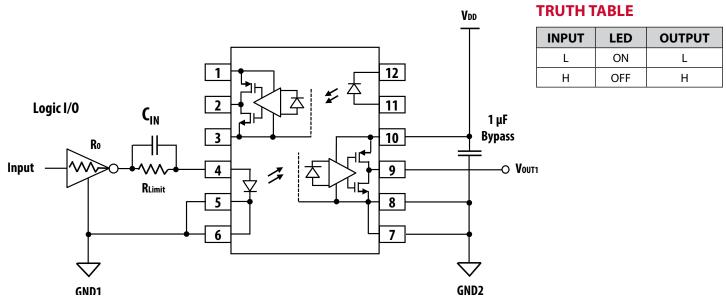


Figure 11: Recommended Application Circuit for ACFL-6211T High Speed Performance

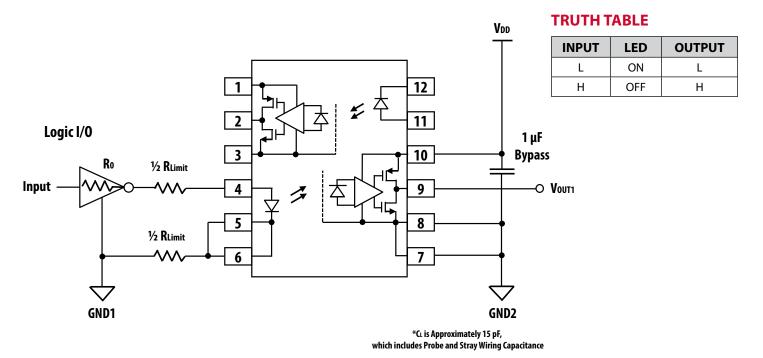


Figure 12: Recommended Application Circuit for ACFL-6212T Low Power Performance

Test Circuits

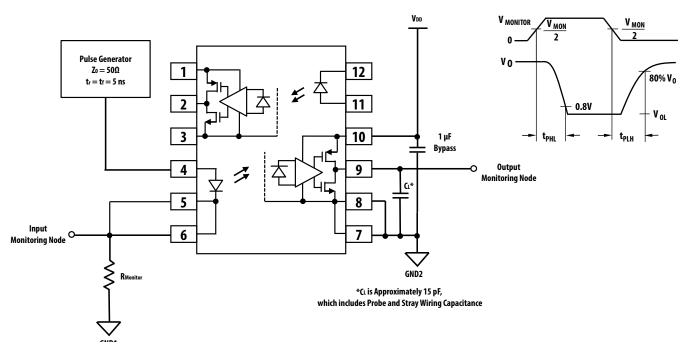


Figure 13: Test Circuit for $t_{PHL},\,t_{PLH},\,t_{F},\,and\,t_{R}$

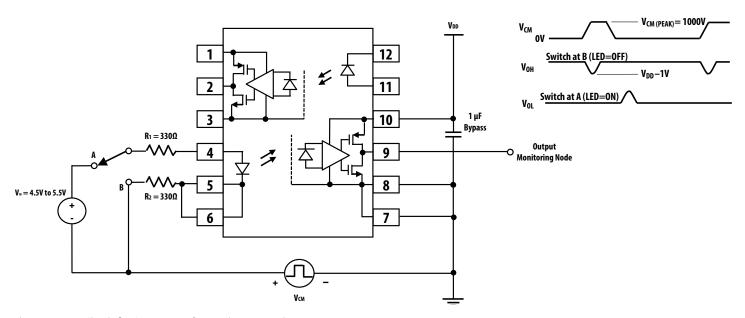


Figure 14: Test Circuit for Common Mode Transient Immunity

Thermal Resistance Measurement

The diagram of ACFL-6211T/6212T for measurement is shown in Figure 15. This is a multi-chip package with four heat sources, the effect of heating of one die due to the adjacent dice are considered by applying the theory of linear superposition. Here, one die is heated first and the temperatures of all the dice are recorded after thermal equilibrium is reached. Then, the second die is heated and all the dice temperatures are recorded and so on until the fourth die is heated. With the known ambient temperature, the die junction temperature and power dissipation, the thermal resistance can be calculated. The thermal resistance calculation can be cast in matrix form. This yields a 4×4 matrix for our case of two heat sources.

R11	R12	R13	R14		P1		ΔΤ1
R21	R22	R23	R24	.,	P2		ΔΤ2
R31	R32	R33	R34	×	Р3	=	ΔΤ3
R41	R42	R43	R44		P4		ΔT4

- R₁₁: Thermal Resistance of Die1 due to heating of Die1 (°C/W)
- R₁₂: Thermal Resistance of Die1 due to heating of Die2 (°C/W)
- R₁₃: Thermal Resistance of Die1 due to heating of Die3 (°C/W)
- R₁₄: Thermal Resistance of Die1 due to heating of Die4 (°C/W)
- R₂₁: Thermal Resistance of Die2 due to heating of Die1 (°C/W)
- R_{22} : Thermal Resistance of Die2 due to heating of Die2 (°C/W)
- R₂₃: Thermal Resistance of Die2 due to heating of Die3 (°C/W)
- R₂₄: Thermal Resistance of Die2 due to heating of Die4 (°C/W)
- R₃₁: Thermal Resistance of Die3 due to heating of Die1 (°C/W)
- R₃₂: Thermal Resistance of Die3 due to heating of Die2 (°C/W)
- R₃₃: Thermal Resistance of Die3 due to heating of Die3 (°C/W)
- R₃₄: Thermal Resistance of Die3 due to heating of Die4 (°C/W)
- R₄₁: Thermal Resistance of Die4 due to heating of Die1 (°C/W)
- R₄₂: Thermal Resistance of Die4 due to heating of Die2 (°C/W)
- R_{43} : Thermal Resistance of Die4 due to heating of Die3 (°C/W)
- n43. Thermal resistance of Die4 due to fleating of Die5 (C/W)
- R_{44} : Thermal Resistance of Die4 due to heating of Die4 (°C/W)
- P₁: Power dissipation of Die1 (W)
- P₂: Power dissipation of Die2 (W)
- P₃: Power dissipation of Die3 (W)
- P₄: Power dissipation of Die4 (W)
- T₁: Junction temperature of Die1 due to heat from all dice (°C)
- T₂: Junction temperature of Die2 due to heat from all dice (°C)
- T₃: Junction temperature of Die3 due to heat from all dice (°C)
- T₄: Junction temperature of Die4 due to heat from all dice (°C)

Ta: Ambient temperature.

- ΔT_1 : Temperature difference between Die1 junction and ambient (°C)
- ΔT_2 : Temperature deference between Die2 junction and ambient (°C)
- ΔT_3 : Temperature difference between Die3 junction and ambient (°C)
- ΔT_4 : Temperature deference between Die4 junction and ambient (°C)

$$T_1 = (R_{11} \times P_1 + R_{12} \times P_2 + R_{13} \times P_3 + R_{14} \times P_4) + Ta - (1)$$

$$T_2 = (R_{21} \times P_1 + R_{22} \times P_2 + R_{23} \times P_3 + R_{24} \times P_4) + Ta - (2)$$

$$T_3 = (R_{31} \times P_1 + R_{32} \times P_2 + R_{33} \times P_3 + R_{34} \times P_4) + Ta - (3)$$

$$T_4 = (R_{41} \times P_1 + R_{42} \times P_2 + R_{43} \times P_3 + R_{44} \times P_4) + T_3 - (4)$$

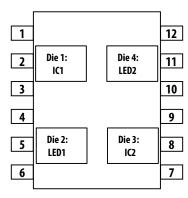


Figure 15: Diagram of ACFL-6211T/6212T for Measurement

Measurement data on a low K (conductivity) board:

 $R_{11} = 181 \, ^{\circ}\text{C/W}$

 $R_{21} = 103 \, ^{\circ}\text{C/W}$

 $R_{31} = 82 \, ^{\circ}\text{C/W}$

 $R_{41} = 110 \, ^{\circ}\text{C/W}$

 $R_{12} = 91 \, ^{\circ}\text{C/W}$

 $R_{22} = 232 \, ^{\circ}\text{C/W}$

 $R_{32} = 97 \, ^{\circ}\text{C/W}$

 $R_{42} = 86 \, ^{\circ}\text{C/W}$

 $R_{13} = 85 \, ^{\circ}\text{C/W}$

 $R_{23} = 109 \, ^{\circ}\text{C/W}$

 $R_{33} = 180 \, ^{\circ}\text{C/W}$

 $R_{43} = 101 \, ^{\circ}\text{C/W}$ $R_{14} = 112 \, ^{\circ}\text{C/W}$

 $R_{24} = 91 \, ^{\circ}\text{C/W}$

 $R_{34} = 91 \, ^{\circ}\text{C/W}$

 $R_{44} = 277 \,^{\circ}\text{C/W}$

Measurement data on a high K (conductivity) board:

 $R_{11} = 117 \, ^{\circ}\text{C/W}$

 $R_{21} = 37 \, ^{\circ}\text{C/W}$

 $R_{31} = 35 \, ^{\circ}\text{C/W}$

 $R_{41} = 47 \, ^{\circ}\text{C/W}$

 $R_{12} = 42 \, ^{\circ}\text{C/W}$

 $R_{22} = 161 \, ^{\circ}\text{C/W}$

 $R_{32} = 53 \, ^{\circ}\text{C/W}$

 $R_{42} = 30 \, ^{\circ}\text{C/W}$

 $R_{13} = 32 \, ^{\circ}\text{C/W}$

 $R_{23} = 39 \, ^{\circ}\text{C/W}$

 $R_{33} = 114 \, ^{\circ}\text{C/W}$

 $R_{43} = 29 \, ^{\circ}\text{C/W}$

 $R_{14} = 60 \, ^{\circ}\text{C/W}$

 $R_{14} = 60^{\circ} \text{ C/W}$ $R_{24} = 33^{\circ} \text{C/W}$

1124 - 33 C/VV

 $R_{34} = 34 \, ^{\circ}\text{C/W}$

 $R_{44} = 189 \, ^{\circ}\text{C/W}$

For product information and a complete list of distributors, please go to our web site: www.broadcom.com.



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